## Search Notes



| Application/Control No. | Applicant(s)/Patent Under Reexamination |
|-------------------------|---|
| 10549801                | FUNAHASHI, MASAKAZU                     |
| Examiner                | Art Unit                                |
| Dawn Garrett            | 1786                                    |

| SEARCHED |  |                 |          |  |
|----------|--|-----------------|----------|--|
| Class    | Subclass   | Date            | Examiner |  |
| 428      | 690, 917 (see EAST search printout for all listed - limited by keywords) | 7-27-08         | DG       |  |
| 313      | 504, 506   | 7-27-08         | DG       |  |
| 257      | E51.05, E51.051  | 7-27-08         | DG       |  |
| 564      | 426, 434   | 7-27-08         | DG       |  |
|          | see EAST search history  | 12/2010; 7/2011 | DG       |  |

| SEARCH NOTES   |                            |          |  |  |
|--|----------------------------|----------|--|--|
| Search Notes   | Date                       | Examiner |  |  |
| EIC 1700 STIC structure search - see printout                                    | 7-22-08                    | DG       |  |  |
| Inventor Name Search   | 7-27-08                    | DG       |  |  |
| EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB         | 7-27-08                    | DG       |  |  |
| updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB | 4-2-2009 and 4-<br>4-2009  | DG       |  |  |
| updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB | 8-19-2009 and<br>8-22-2009 | DG       |  |  |
| updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB | 5-12-2010                  | DG       |  |  |
| updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB | 12-16-2010                 | DG       |  |  |
| updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB | 7-27-2011                  | DG       |  |  |

| INTERFERENCE SEARCH |          |      |          |
|---------------------|----------|------|----------|
| Class               | Subclass | Date | Examiner |
|                     |          |      |          |

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